

2024 IEEE Radiation Effects Data Workshop (REDW 2024) (in conjunction with 2024 NSREC)

**Ottawa, Ontario, Canada
22-27 July 2024**



**IEEE Catalog Number: CFP24422-POD
ISBN: 979-8-3503-8208-2**

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IEEE Catalog Number:	CFP24422-POD
ISBN (Print-On-Demand):	979-8-3503-8208-2
ISBN (Online):	979-8-3503-8207-5
ISSN:	2154-0519

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